

ISO/IEC 30192:2016-06 (E)

Information technology - Digitally recorded media for information interchange and storage - 120 mm Single Layer (25,0 Gbytes per disk) and Dual Layer (50,0 Gbytes per disk) BD Rewritable disk

Contents		Page
1	Scope	1
2	Conformance	2
2.1	Optical Disk	2
2.2	Generating system	2
2.3	Receiving system	2
2.4	Compatibility statement	2
3	Normative references	2
4	Terms and definitions	3
5	Conventions and notations	7
5.1	Terminology	7
5.1.1	Meaning of words	7
5.1.2	Levels of grouping	7
5.2	Representation of numbers	7
5.3	Integer calculus	8
5.4	Names	8
6	List of acronyms	8
7	General descriptions of disk	11
8	General requirements	13
8.1	Environments	13
8.1.1	Test environment	13
8.1.2	Operating environment	13
8.1.3	Storage environment	14
8.1.4	Transportation	15
8.2	Safety requirements	15
8.3	Flammability	15
9	Reference drive	15
9.1	General	15
9.2	Environmental conditions	15
9.3	Optical system	15
9.4	Optical beam	17
9.5	HF read channel	17
9.6	Radial PP read channel	18
9.7	Disk Clamping	18
9.8	Rotation of the disk and Measurement Velocity	18
9.9	Normalized servo transfer function	19
9.10	Measurement Velocity and Reference servo for axial tracking	20
9.11	Measurement Velocity and Reference servo for radial tracking	21
10	Dimensional characteristics	22
10.1	General	22
10.2	Disk reference planes and reference axis	22

10.3	Overall dimensions	23
10.4	First transition Area	24
10.5	Protection ring	24
10.6	Clamping Zone	24
10.7	Second transition Area	24
10.8	Information Area	25
10.8.1	General	25
10.8.2	Subdivisions of Information Zone on SL disk	25
10.8.3	Subdivisions of Information Zone on DL disks	26
10.9	Rim Area	27
11	Mechanical characteristics	27
11.1	Mass	27
11.2	Moment of inertia	27
11.3	Dynamic imbalance	27
11.4	Axial runout	27
11.4.1	General	27
11.4.2	Residual axial tracking error	28
11.5	Radial runout	28
11.5.1	General	28
11.5.2	Residual radial tracking error on SL disks	28
11.5.3	Residual radial tracking error on DL disks	29
11.6	Durability of Cover Layer	29
11.6.1	Impact resistance of Cover Layer	29
11.6.2	Scratch resistance of Cover Layer	29
11.6.3	Repulsion of fingerprints by Cover Layer	29
12	Optical characteristics in Information Area	29
12.1	General	29
12.2	Refractive index of Transmission Stacks (TS)	29
12.3	Thickness of Transmission Stack(s)	30
12.3.1	Thickness of Transmission Stack of SL disks	30
12.3.2	Thickness of Transmission Stack of DL disks	30
12.4	Reflectivity	31
12.4.1	Reflectivity of Recording Layer of SL disks	31
12.4.2	Reflectivity of Recording Layer of DL disks	32
12.5	Birefringence	32
12.6	Angular deviation	32
13	Data format	33
13.1	General	33
13.2	Data Frames	35
13.3	Error-Detection Code (EDC)	35
13.4	Scrambled Data Frame	35
13.5	Data Block	36
13.6	LDC Block	37
13.7	LDC Code words	37
13.8	LDC Cluster	38
13.8.1	General	38
13.8.2	First interleave step	38
13.8.3	Second interleaving step	39
13.9	Addressing and Control Data	41
13.9.1	General	41
13.9.2	Address Units	41
13.9.3	User-Control Data	44
13.9.4	Byte/Bit assignments for User-Control Data	45
13.10	Access Block	45
13.11	BIS Block	47
13.12	BIS Code words	47
13.13	BIS Cluster	48
13.14	ECC Cluster	52
13.15	Recording Frames	53

13.16	Physical Cluster	53
13.17	17PP Modulation for Recordable data	53
13.17.1	General	53
13.17.2	Bit conversion rules	54
13.17.3	dc-control procedure	54
13.17.4	Frame Sync	54
13.18	Modulation and NRZI conversion	56
14	Physical Data Allocation and Linking	57
14.1	General	57
14.2	Recording-Unit Block (RUB)	57
14.2.1	General	57
14.2.2	Data Run-in	57
14.2.3	Data Run-out	58
14.2.4	Guard_3 field	59
14.3	Locating data relative to wobble addresses	60
14.3.1	General	60
14.3.2	Start-Position Shift (SPS)	60
15	Track format	61
15.1	General	61
15.2	Track shape	62
15.3	Track Path	64
15.4	Track Pitch	64
15.4.1	Track Pitch in BCA Zone	64
15.4.2	Track Pitch in Embossed HFM Areas	64
15.4.3	Track Pitch in Rewritable Areas	64
15.4.4	Track Pitch between Embossed HFM Area and Rewritable Area	65
15.5	Track layout of HFM Groove	65
15.5.1	General	65
15.5.2	Data Format	65
15.5.3	Addressing and Control Data	66
15.5.4	Recording Frames	69
15.6	Track layout of Wobbled Groove(s)	71
15.6.1	General	71
15.6.2	Modulation of wobbles	72
15.7	ADIP Information	73
15.7.1	General	73
15.7.2	ADIP-Unit Types	73
15.7.3	ADIP Word structure	75
15.7.4	ADIP Data structure	76
15.7.5	ADIP Error Correction	78
15.8	Disk Information in ADIP Aux Frame	80
15.8.1	General	80
15.8.2	Error protection for Disk-Information Aux Frames	80
15.8.3	Disk-Information Data structure	81
16	General description of Information Zone	112
16.1	General	112
16.2	Format of Information Zone on Single-Layer disk	112
16.3	Format of Information Zone on Dual-Layer disk	112
17	Layout of Rewritable Area of Information Zone	112
18	Inner Zone	116
18.1	General	116
18.2	Permanent Information & Control data (PIC) Zone	118
18.2.1	General	118
18.2.2	Content of PIC Zone	118
18.2.3	Emergency Brake	119
18.3	Rewritable Area of Inner Zone(s)	121
18.3.1	Protection-Zone 2	121

18.3.2	INFO 2 / Reserved 8	121
18.3.3	INFO 2 / Reserved 7	121
18.3.4	INFO 2 / Reserved 6	121
18.3.5	INFO 2 / Reserved 5	122
18.3.6	INFO 2 / PAC 2	122
18.3.7	INFO 2 / DMA 2	122
18.3.8	INFO 2 / Control Data 2	122
18.3.9	INFO 2 / Buffer 2	122
18.3.10	OPC / Test Zone	122
18.3.11	Reserved	122
18.3.12	INFO1 / Buffer 1	122
18.3.13	INFO 1 / Drive Area (optional)	122
18.3.14	INFO 1 / Reserved 3	124
18.3.15	INFO 1 / Reserved 2	124
18.3.16	INFO 1 / Reserved 1	124
18.3.17	INFO 1 / DMA 1	124
18.3.18	INFO1 / Control Data 1	124
18.3.19	INFO1 / PAC 1	124
19	Data Zone	124
20	Outer Zone(s)	125
20.1	General	125
20.2	INFO 3 / Buffer 4	126
20.3	INFO 3 / DMA 3	126
20.4	INFO 3 / Control Data 4	126
20.5	Angular buffer	126
20.6	INFO 4 / DMA 4	126
20.7	INFO 4 / Control Data 4	126
20.8	INFO 4 / Buffer 6	126
20.9	Protection-Zone 3	126
21	Physical-Access Control Clusters	127
21.1	General	127
21.2	Layout of PAC Zones	127
21.3	General structure of PAC Clusters	128
21.4	Primary PAC Cluster (mandatory)	131
21.5	Disk Write-Protect PAC Cluster (optional)	134
21.6	IS1 and IS2 PAC Clusters	137
22	Disk Management	138
22.1	General	138
22.2	Disk-Management Structure (DMS)	138
22.2.1	General	138
22.2.2	Disk-Definition Structure (DDS)	139
22.2.3	Defect List (DFL)	143
22.2.4	Defect-List Header (DLH)	143
22.2.5	List of Defects	144
22.2.6	DFL Entries	146
23	Assignment of Logical-Sector Numbers (LSNs)	147
24	Characteristics of Grooved Areas	148
25	Method of testing for Grooved Area	148
25.1	General	148
25.2	Environment	148
25.3	Reference drive	148
25.3.1	General	148
25.3.2	Read power	148
25.3.3	Read channels	148
25.3.4	Tracking requirements	149

25.3.5	Scanning velocity	149
25.4	Definitions of signals	149
26	Signals from HFM Grooves	151
26.1	Push-Pull signal	151
26.2	HFM Wobble signal	151
26.3	Jitter of HFM signal	151
27	Signals from Wobbled Groove(s)	152
27.1	Phase depth	152
27.2	Push-Pull signal	152
27.3	Wobble signal	152
27.3.1	General	152
27.3.2	Measurement of NWS	152
27.3.3	Measurement of wobble CNR	152
27.3.4	Measurement of harmonic distortion requirements	153
28	Characteristics of Recording Layer	153
29	Method of testing for Recording Layer	154
29.1	General	154
29.2	Environment	154
29.3	Reference drive	154
29.3.1	General	154
29.3.2	Read power	154
29.3.3	Read channels	154
29.3.4	Tracking requirements	154
29.3.5	Scanning velocities	154
29.4	Write conditions	154
29.4.1	Write-pulse waveform	154
29.4.2	Write powers	155
29.4.3	Write conditions for jitter measurement	155
29.4.4	Write conditions for cross-erase measurement	155
29.4.5	Write conditions for inter-velocity overwrite measurements	155
29.5	Definition of signals	156
30	Signals from Recorded Areas	156
30.1	HF signals	156
30.2	Modulated amplitude	156
30.3	Reflectivity-Modulation product	157
30.4	Asymmetry	157
30.5	Jitter	157
30.6	Cross-erase	158
30.7	Inter-velocity overwrite	158
30.8	Read stability	159
31	Local defects	160
32	Characteristics of User Data	160
33	Method of testing for User Data	160
33.1	General	160
33.2	Environment	160
33.3	Reference drive	161
33.3.1	General	161
33.3.2	Read power	161
33.3.3	Read channels	161
33.3.4	Error Correction	161
33.3.5	Tracking requirements	161
33.3.6	Scanning velocities	161
33.4	Definition of signals	161

34	Minimum quality of recorded information	163
34.1	Random Symbol Error Rate	163
34.2	Maximum burst errors	163
34.3	User-written Data	163
35	BCA	164
Annex A (normative) Thickness of Transmission Stacks in case of multiple layers		165
A.1	General	165
A.2	Refractive Index n_i of all layers in Cover Layer and Spacer Layer	165
A.3	Thickness variation of the Transmission Stack	165
A.4	Example of thickness calculation for SL	165
Annex B (normative) Measurement of reflectivity		166
B.1	General	166
B.2	Calibration method	167
B.3	Measuring method	168
Annex C (normative) Measurement of scratch resistance of Cover Layer		169
C.1	General	169
C.2	Taber Abrasion test	169
Annex D (normative) Measurement of repulsion of grime by Cover Layer		171
D.1	General	171
D.2	Specifications of stamp	171
D.3	Preparation of ink	172
D.4	Preparation of ink pad	172
D.5	Using ink pad and stamp	173
Annex E (normative) Measurement of wobble amplitude		174
E.1	Measurement methods	174
E.2	Calibration of filters	178
Annex F (normative) Write-pulse waveform for testing		179
F.1	General write-pulse waveform	179
F.2	N-1 write strategy A	179
F.3	N-1 write strategy B	181
F.4	N/2 write strategy	183
F.5	Definition of pulse widths and rise and fall times	186
Annex G (normative) Optimum Power Control (OPC) procedure for disk		187
G.1	General	187
G.2	Mathematical model for modulation versus power function	187
G.3	Procedure for determination of OPC parameters for disk	188
G.4	Write-power window	189
Annex H (normative) HF signal pre-processing for jitter measurements		190
H.1	General	190
H.2	General implementation of equalizer	190
H.3	Conventional Equalizer circuit	191
H.4	Limit Equalizer circuit	192
H.5	Specifications of supporting circuits	193
H.5.1	Amplifiers and filters	193
H.5.2	Open-loop transfer function for PLL	194

H.5.3	Slicer	195
H.6	Condition for measurement	195
H.7	Jitter measurement	196
Annex I (normative) Measurement procedure		197
I.1	General	197
I.2	Initial adjustments of Reference drive	197
I.3	Jitter measurement	197
I.4	Modulated amplitude measurements	198
I.5	Measurements of Resolution I2pp / I8pp and I3pp / I8pp	198
I.5.1	Method for measuring I2pp and I8pp	198
I.5.2	I3pp / I8pp, I8pp / I8H and asymmetry measurement procedure	199
I.6	Tracking-error signal measurements (PPnorm measurement procedure)	200
I.7	Residual error of axial tracking measurement procedure	201
I.8	Residual error of radial tracking measurement procedure	202
I.9	Random SER measurement	202
Annex J (informative) Measurement of birefringence		203
J.1	Principle of measurement	203
J.2	Measurements conditions	203
J.3	Example of measurement procedure	203
J.4	Interchangeability of measuring results	204
Annex K (informative) Measurement of thickness of Cover Layer and Spacer Layer		205
K.1	Focusing method	205
K.2	Interferometer method	206
Annex L (informative) Measurement of impact resistance of Cover Layer		208
L.1	General	208
L.2	Recommendation for drives	208
L.3	Measurements of impact resistance of Cover Layer	208
Annex M (informative) Groove deviation and wobble amplitude		210
M.1	Relation between normalized wobble signal and wobble amplitude	210
M.2	Tolerance of normalized wobble signal	210